
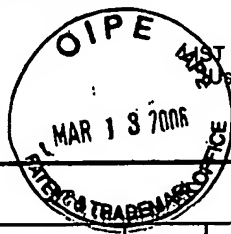


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H0004116-US	SERIAL NO. 10/614,807		
<div style="float: left; width: 15%;">  </div> <div style="float: right; width: 85%;"> LIST OF ART CITED BY APPLICANT (Use several sheets if necessary) </div> <div style="clear: both;"></div>				APPLICANT Wuwen Yi et al.			
				FILING DATE July 9, 2003	GROUP 1742		
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
HW	AA	2002/0041819 A1	04/02	Kumar et al.			
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
	AF						
	AG						
	AH						
	AI						
	AJ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AK	V. Pavate et al., <i>Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and in-film defect density</i> , pp. 42-47, SPIE Vol. 3214, 1997					
	AL						
EXAMINER /Harry Wilkins/		DATE CONSIDERED 04/24/2006					
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							

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U.S. PATENT DOCUMENTS					
*Examiner Initial		Document Number	Date	Name	Filing Date If Appropriate
HW	AA	6,192,969	02/01	Bunn et al.	
HW	AB	6,569,270 B2	05/03	Segal	
HW	AC	<del>6,669,805 B2 A1</del> 2003/0005200A1	03/03	Segal et al.	
	AD				
	AE				
	AF				
	AG				
FOREIGN PATENT DOCUMENTS					
		Document Number	Date	Country	Class Subclass Translation
	AH				Yes No
	AI				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)					
HW	AJ		C.A. Michaluk, et al. <i>Methodologies for Determining the Global Texture of Tantalum Plate Using X-Ray Diffraction</i> , The Minerals, Metals & Materials Society, pps. 123-131, 1996.		
	AK				
EXAMINER /Harry Wilkins/		DATE CONSIDERED 04/24/2006			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					